

SEMI F47 Voltage Sag Immunity Test Report for Power Supply QS10.241



Other devices covered by this report: OS10.241-www Standard units

QS10.241	-ww	Standard units
ww:	blank	Standard unit
	C1	Version with conformal coated pc-boards
	75	Same as QS10.241 but with assembled wall mount bracket
	A1	Version with conformal coated pc-boards and ATEX/IECEx approval
	D1	Version with enhanced DC-Input range

SEMI F47 Test Report



Document Number	QS10.241 Semi F47 Rev2 TR1	
Approval Order Number	LAB 20-806	
Standards	 SEMI F47-0706 (July 2006) SPECIFICATION FOR SEMICONDUCTOR PROCESSING EQUIPMENT - Voltage Sag Immunity Compliance Tests IEC 61000-4-11 2004 +A1:2017 Electromagnetic compatibility (EMC) - Part 4-11: Testing and measurement techniques - Voltage dips, short interruptions and voltage variations immunity tests for equipment with input current up to 16 A per phase 	
Applicant	PULS GmbH Elektrastraße 6 81925 Munich, Germany	
Test Laboratory	PULS Vario GmbH Kranichberggasse 6 1120 Vienna, Austria	
Test Engineer	Thomas Ramel	
Test Date	23.06.2020 - 04.08.2020	
Description of Test Device	Built-in power supplies for	or DIN-Rail mounting
Devices under Evaluation	QS10.241 Input: AC 100-240V, Output: DC 24-28V, 10A	
S/N of Devices	QS10.241: S/N: 20117261 C	
Application Details	Input voltage: Input frequency: Output load:	1-Phase AC 120V, 208V 50 or 60Hz 240W



PASS/FAIL Criterions:

Test Result:

PASS

value

The test device passed all essential SEMI F47-0706 tests according to the defined application details without any limitations and is qualified to bear the following approval mark:

The output voltage is not allowed to deviated more than 5% of the initial

DC OK contact is not allowed to trigger during and after the test

In accordance with paragraph 7.8.2 a) of SEMI F47-0706



Since DC power supplies, as covered in this test report, are only components of a semiconductor processing equipment, the tests of the SEMI F47 standard were conducted with selected rated characteristics of the DC power supply.

The system integrator of the final semiconductor processing equipment needs to judge if the results of this test report are compatible with the SEMI F47 requirements of his system or if test data under other operating conditions are additionally required.

The system integrator also needs to judge if the results of the inrush current peaks are compatible with the selected external fuses for input protection.

The system integrator also needs to be aware about aging effects. It is expected that the ride through time can be reduced by 15% at end of the specified lifetime expectancy.

A SEMI F47 certificate is not intended for this type of component, however the product fulfils the general requirements and can be marked with the following symbol.

Approved

Harald Etlinger Sr. Qualification Eng. PULS Vario GmbH, Vienna

Date of Approval

04.08.2020



Copy of marking plate:



List of Test Equipment

Туре	Model	Inventory number
Test generator	Kikusui PCR3000WE2	10381
el. Load	el. Load Chroma 63201	10046
Oscilloscope	LeCroy WS454	10130
Oscilloscope	LeCroy WS424	10127
Diffential Probe	Lecroy	10246
Current Probe	LeCroy CP30	10378

The test equipment complies with the requirements of IEC 61000-4-11.

The peak current capability of the test generator was evaluated according Annex A of IEC 61000-4-11 and is able to deliver minimum 32.7A.

Test Specification for SEMI F47 compliance

Voltage Sag Immunity according to the following table:

Sag depth#1	Duration	Duration at 50 Hz	Duration at 60 Hz
50%	200ms	10 cycles	12 cycles
70%	500ms	25 cycles	30 cycles
80%	1000ms	50 cycles	60 cycles

#1 Sag depth is expressed in percent of remaining nominal voltage. For example, during a 70% voltage sag on a 200 volt nominal system, the voltage is reduced during the sag to 140 volts and not 60 volts.



Test Setup

The unit under test in normal operating condition mounted in climate chamber. The input is connected to an AC Source. The input voltage is measured with a 100:1 differential probe and the input current is measured with current probes. These probes are connected to oscilloscopes.

The output is connected to an active load. The output voltage is connected directly to the oscilloscope. "DC-OK" signal is also measured with an oscilloscope.

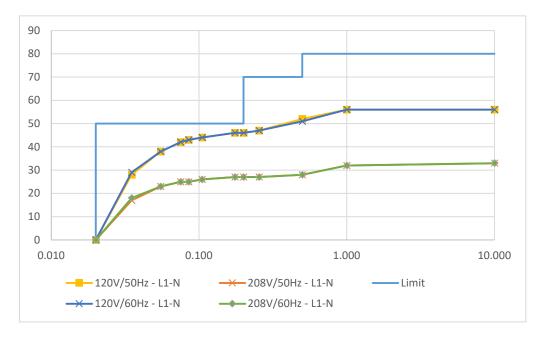
Input and output voltages are measured with oscilloscope #1 and input currents with oscilloscope #2.

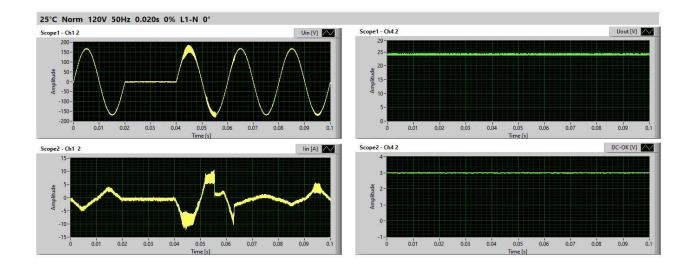


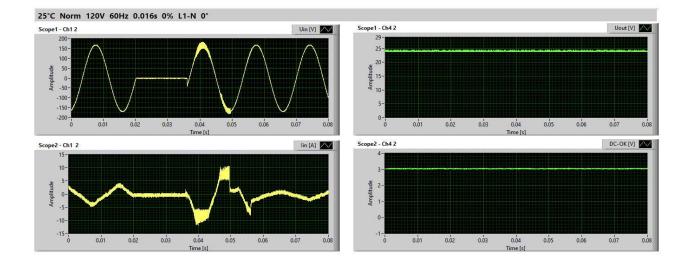




Voltage Sag Results

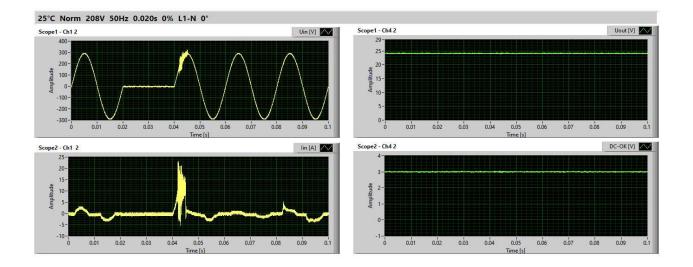


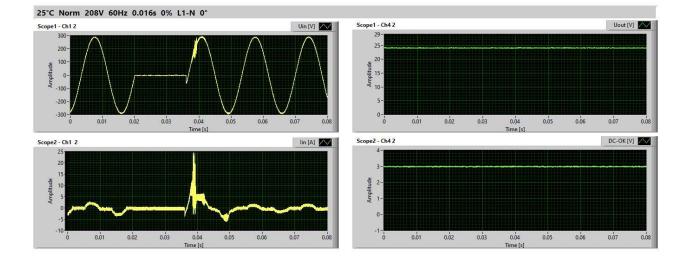




Date: 04.08.2020









Conducted Tests at 120V 50Hz

Input Voltage	120Vac
Input Frequency	50Hz
Output Voltage	24V
Output Current	10A
Ambient Temperature	25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0.020	0	10.6	-12.2
0.200	50	9.4	-10.9
0.500	70	6.6	-8.4
1	80	5.6	-6.9
10	80	5.6	-6.6

Informational measurements

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0.020	0	0.175	46
0.035	28	0.200	46
0.055	38	0.255	47
0.075	42	0.500	52
0.085	43	1	56
0.105	44	10	56

Conducted Tests at 120V 60Hz

Input Voltage	120Vac
Input Frequency	60Hz
Output Voltage	24V
Output Current	10A
Ambient Temperature	25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0.016	0	10.6	-11.9
0.200	50	9.7	-10.6
0.500	70	6.9	-8.4
1	80	5.6	-7.2
10	80	5.6	-6.6

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0.016	0	0.175	46
0.035	29	0.200	46
0.055	38	0.255	47
0.075	42	0.500	51
0.085	43	1	56
0.105	44	10	56



Conducted Tests at 208V 50Hz

Input Voltage	208Vac
Input Frequency	50Hz
Output Voltage	24V
Output Current	10A
Ambient Temperature	25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0.020	0	23.1	-5.3
0.200	50	9.7	-10
0.500	70	7.2	-5.3
1	80	5.3	-4.4
10	80	5	-3.7

Informational measurements

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0.020	0	0.175	27
0.035	17	0.200	27
0.055	23	0.255	27
0.075	25	0.500	28
0.085	25	1	32
0.105	26	10	33

Conducted Tests at 208V 60Hz

Input Voltage	208Vac
Input Frequency	60Hz
Output Voltage	24V
Output Current	10A
Ambient Temperature	25°C

Sag duration [s]	Voltage remaining [%]	Pos. peak current [A]	Neg. peak current [A]
0.016	0	24.7	-5.9
0.200	50	9.4	-9.7
0.500	70	6.9	-6.6
1	80	5	-4.4
10	80	5	-4.4

Sag duration [s]	Voltage remaining [%]	Sag duration [s]	Voltage remaining [%]
0.016	0	0.175	27
0.035	18	0.200	27
0.055	23	0.255	27
0.075	25	0.500	28
0.085	25	1	32
0.105	26	10	33



Inrush current measurements according 61000-4-11 at 208V 50Hz

Input Voltage	208Vac
Input Frequency	50Hz
Output Voltage	24V
Output Current	10A
Ambient Temperature	25°C

Peak input current measurements on unit under test:

First two measurements turn off input power for EUT for 5 minutes and then

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Measure peak input current when AC turned on at 90°:	4.1A

Measure peak input current when AC turned on at 270°: 4.1A

Next two measurements turn on the input power for EUT for at least 1 minute then turn off input power for 5s and on again.

Measure peak input current when AC turned on at 90°:	4.1A
Measure peak input current when AC turned on at 270°:	3.7A

Inrush current measurements according 61000-4-11 at 208V 60Hz

Input Voltage	208Vac
Input Frequency	60Hz
Output Voltage	24V
Output Current	10A
Ambient Temperature	25°C

Peak input current measurements on unit under test:

First two measurements turn off input power for EUT for 5 minutes and then

Measure peak input current when AC turned on at 90°:	4.7A
Measure peak input current when AC turned on at 270°:	5.6A
on again.	
Measure peak input current when AC turned on at 90°:	4.1A

Measure peak input current when AC turned on at 270°: 5A



Operating conditions and their influence in test results:

a) Ambient temperature:

Control measurements show that the ambient temperature has only a minor influence in the ride-through time test results.

Depending on the used topology to reduce the input inrush current, the ambient temperature can have a major influence in the arising peak current after the sag test. Therefore, tests were performed at ambient temperatures of 25°C and +60°C.

It is assumed that semiconductor processing equipment is never used at lower temperatures than +25°C. Although the power supply itself is specified down to -25°C, a test at such low temperatures is not performed.

b) Mains frequency 50Hz vs. 60Hz:

Control measurements show that 50Hz testing is more critical than 60Hz testing. Therefore, unless otherwise noted, all tests were performed with a mains frequency of 50Hz.

c) Output voltage 24V vs. 28V:

The ride-through time depend on the stored energy in the input capacitors and the amount of output power. The output voltage is not essential as long as the output power is constant.

The adjusted output voltage has no influence in input currents peaks after input voltage sags. Therefore, unless otherwise noted, all tests were performed with an output voltage of 24Vdc.

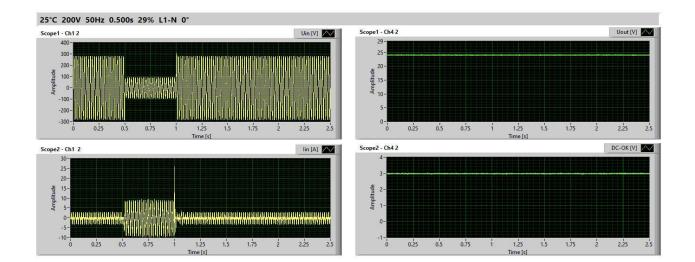


APPENDIX

Informational measurements at 200V

Input Voltage	200Vac
Input Frequency	50Hz
Output Voltage	24V
Output Current	10A
Ambient Temperature	25°C

Sag duration	Voltage remaining	Positive peak current	Negative peak current
[s]	[%]	[A]	[A]
0.020	0	24.1	-6.2
0.035	18	23.1	-25
0.055	24	17.2	-25.6
0.075	26	10.9	-25.3
0.085	26	25.3	-15.6
0.105	27	24.7	-11.2
0.175	28	9.7	-24.4
0.200	28	23.1	-10.3
0.255	28	11.6	-23.4
0.500	29	25.9	-9.7
1	33	18.1	-10.9
10	34	9.7	-9.4





Informational measurements at 230V

Input Voltage	230Vac
Input Frequency	50Hz
Output Voltage	24V
Output Current	10A
Ambient Temperature	25°C

Sag duration [s]	Voltage remaining [%]	Positive peak current [A]	Negative peak current [A]
0.020	0	23.1	-5.9
0.035	16	11.2	-27.2
0.055	21	10.9	-30
0.075	23	10	-26.2
0.085	23	25.3	-10.3
0.105	23	31.9	-11.2
0.175	24	10.3	-29.7
0.200	24	21.2	-10.3
0.255	25	9.4	-23.7
0.500	25	22.8	-10
1	28	18.4	-10.3
10	30	10.3	-9.4

